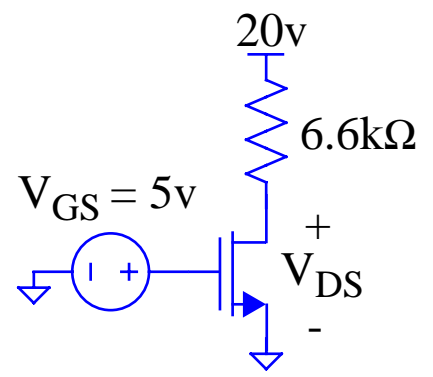
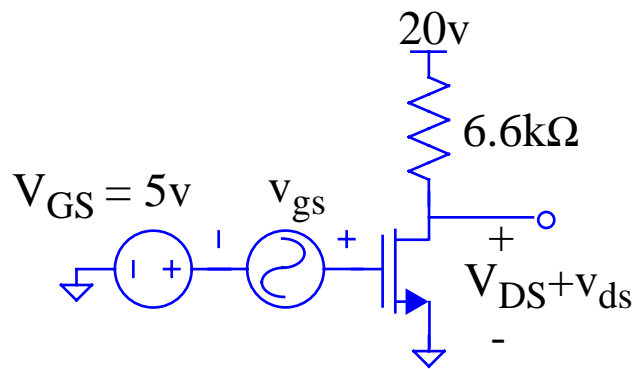
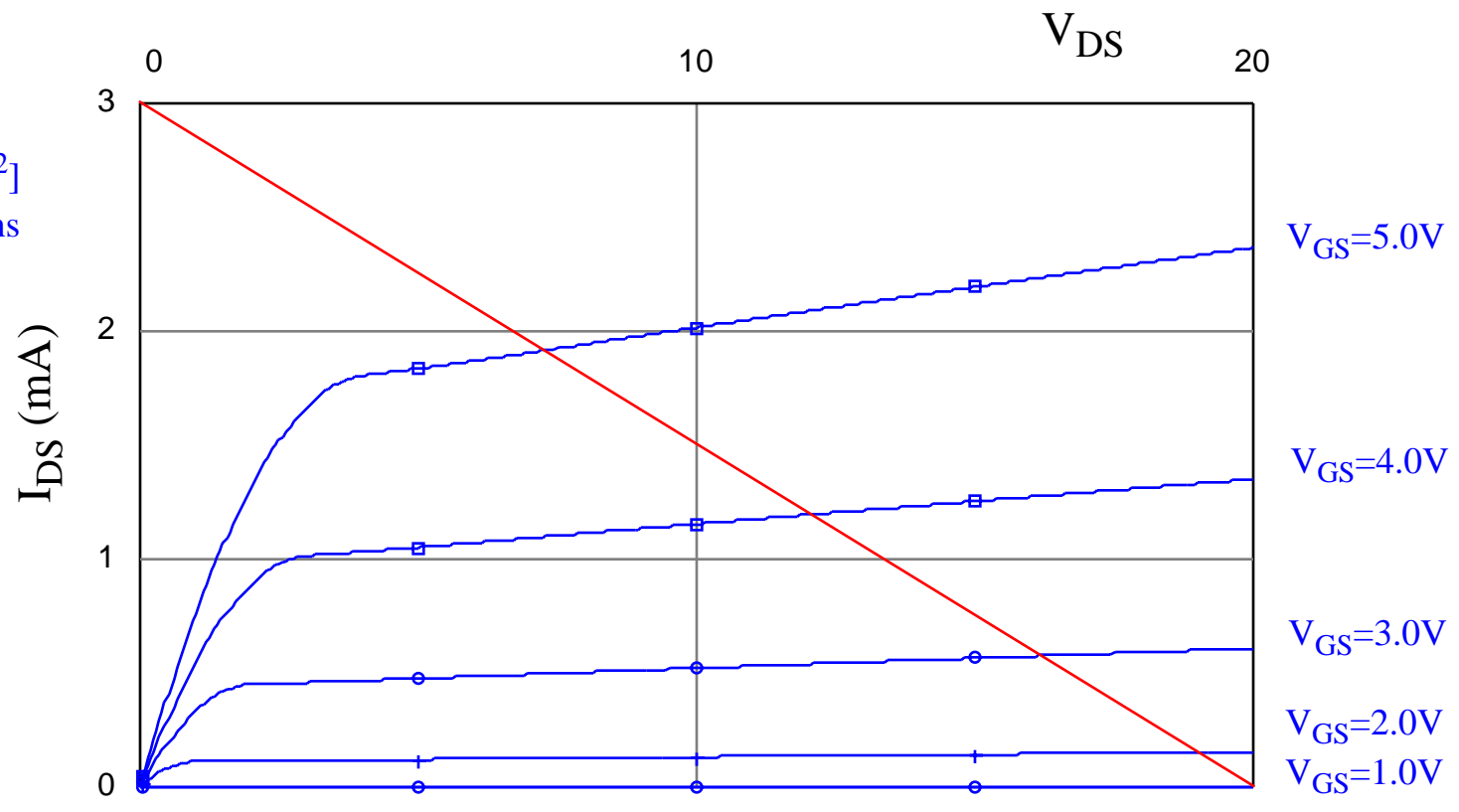


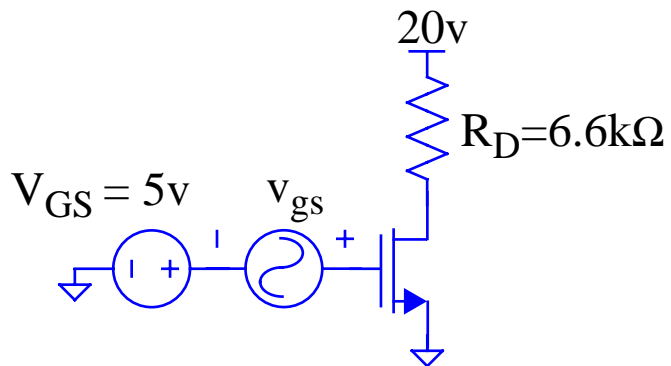
FET Amplifiers



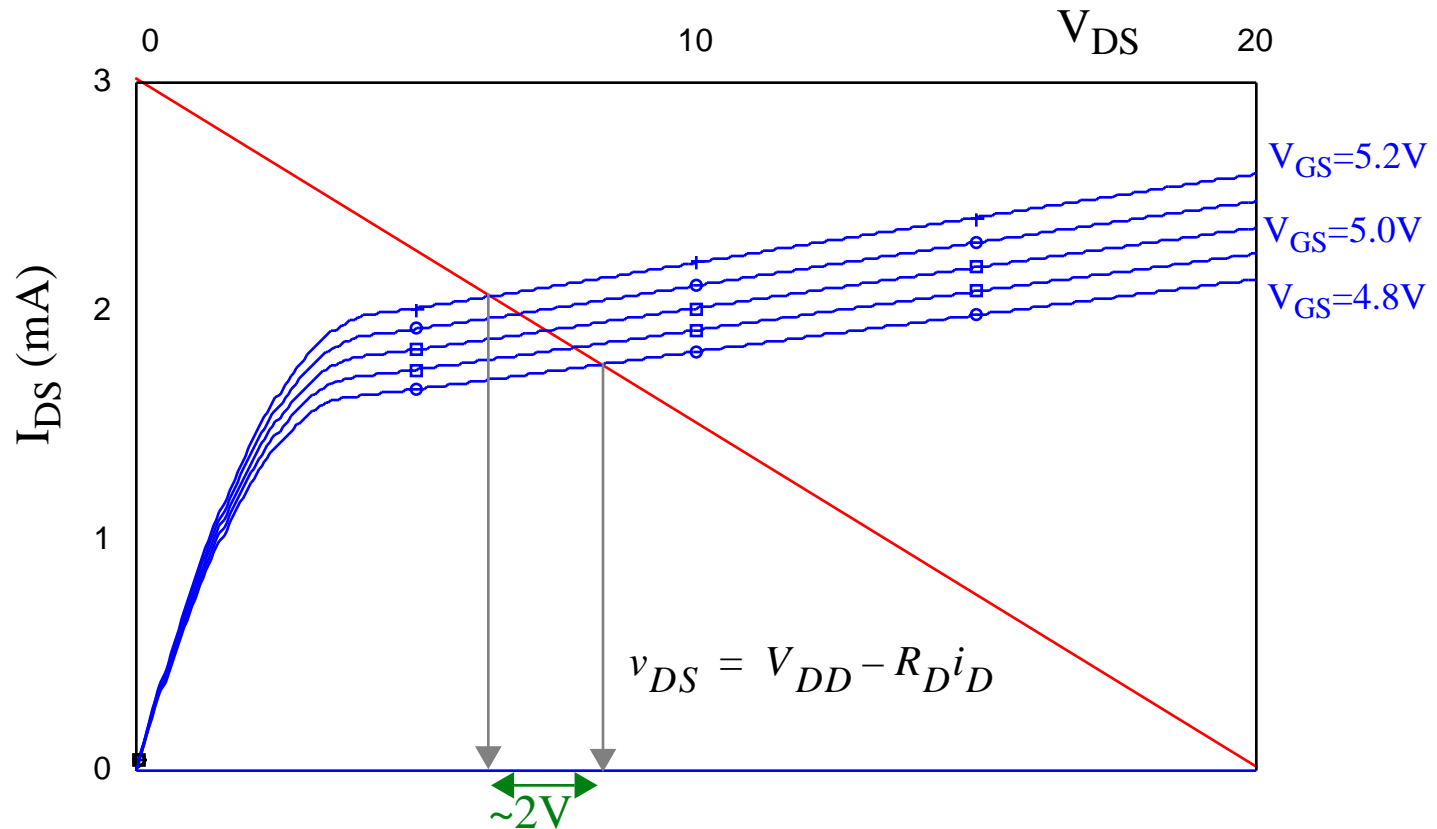
$V_{T0} = 1.0\text{V}$
 $K_p = 2 \times 10^{-5} \text{ [A/V}^2\text{]}$
 $W = 100 \text{ microns}$
 $L = 10 \text{ microns}$



FET Amplifiers

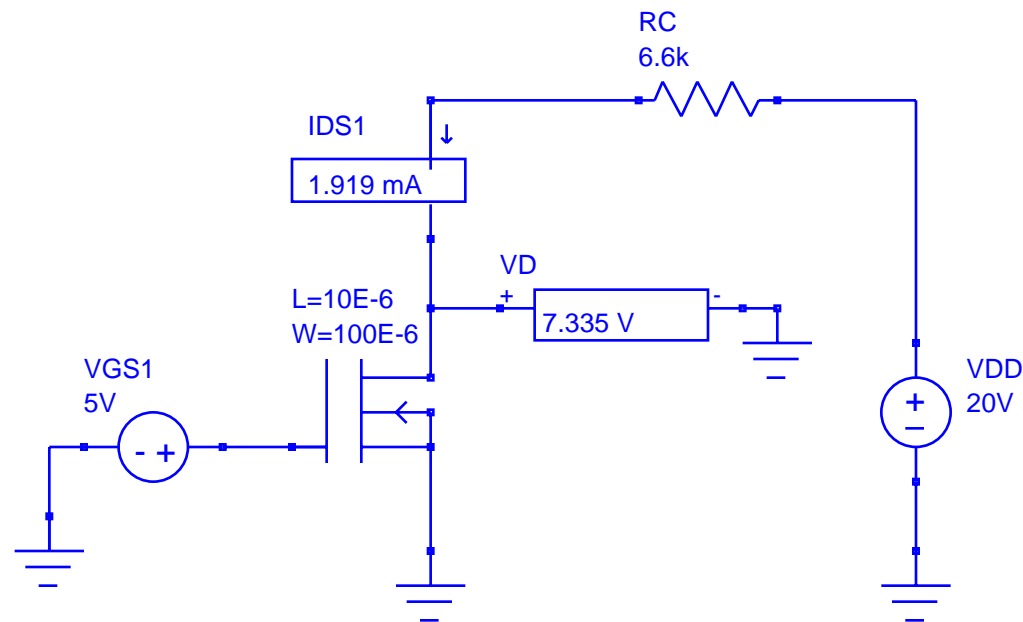


- A 200mv peak ac input voltage will cause more than a 1v peak ac output voltage
- What would we change to make the voltage gain even larger?



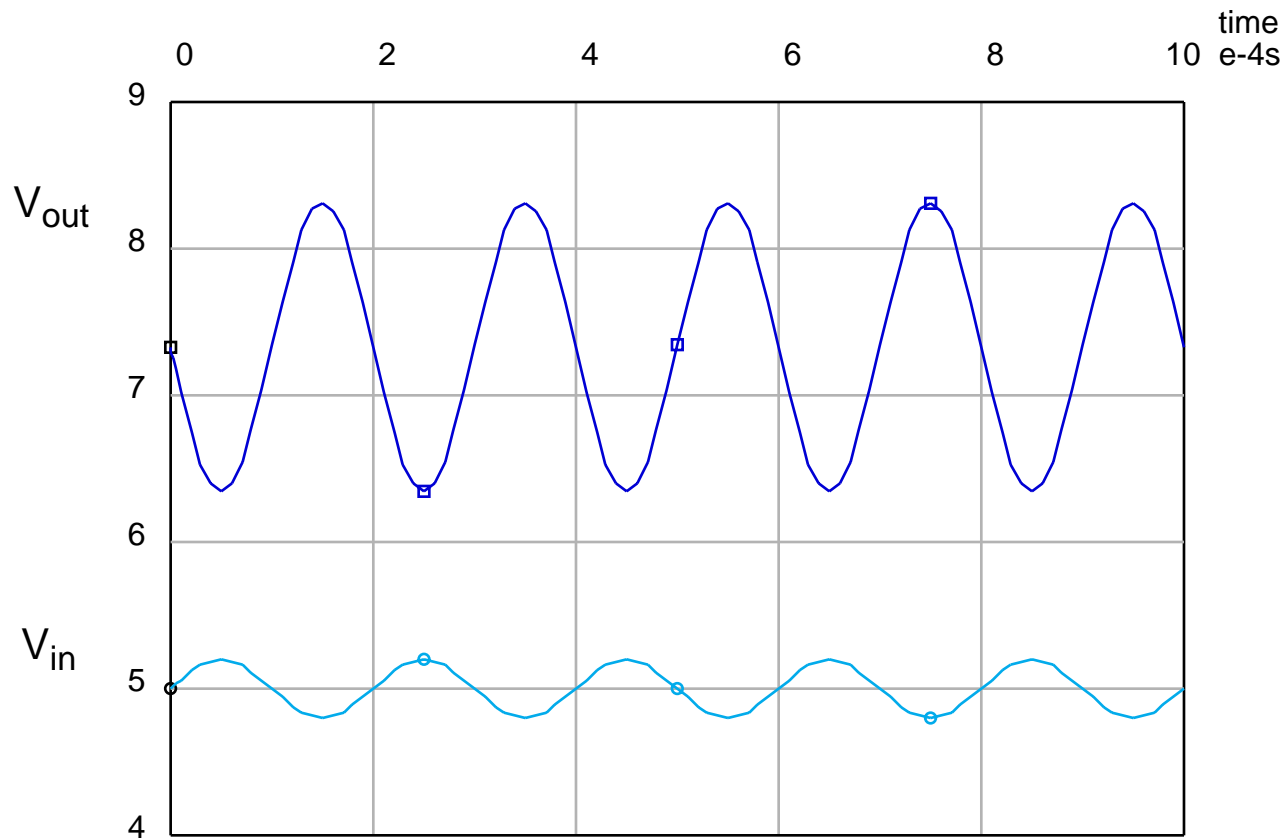
dc Solution of FET Amplifier

- Set the ac source to zero and analyze the dc bias point
- Solution should agree with that from load line approximation



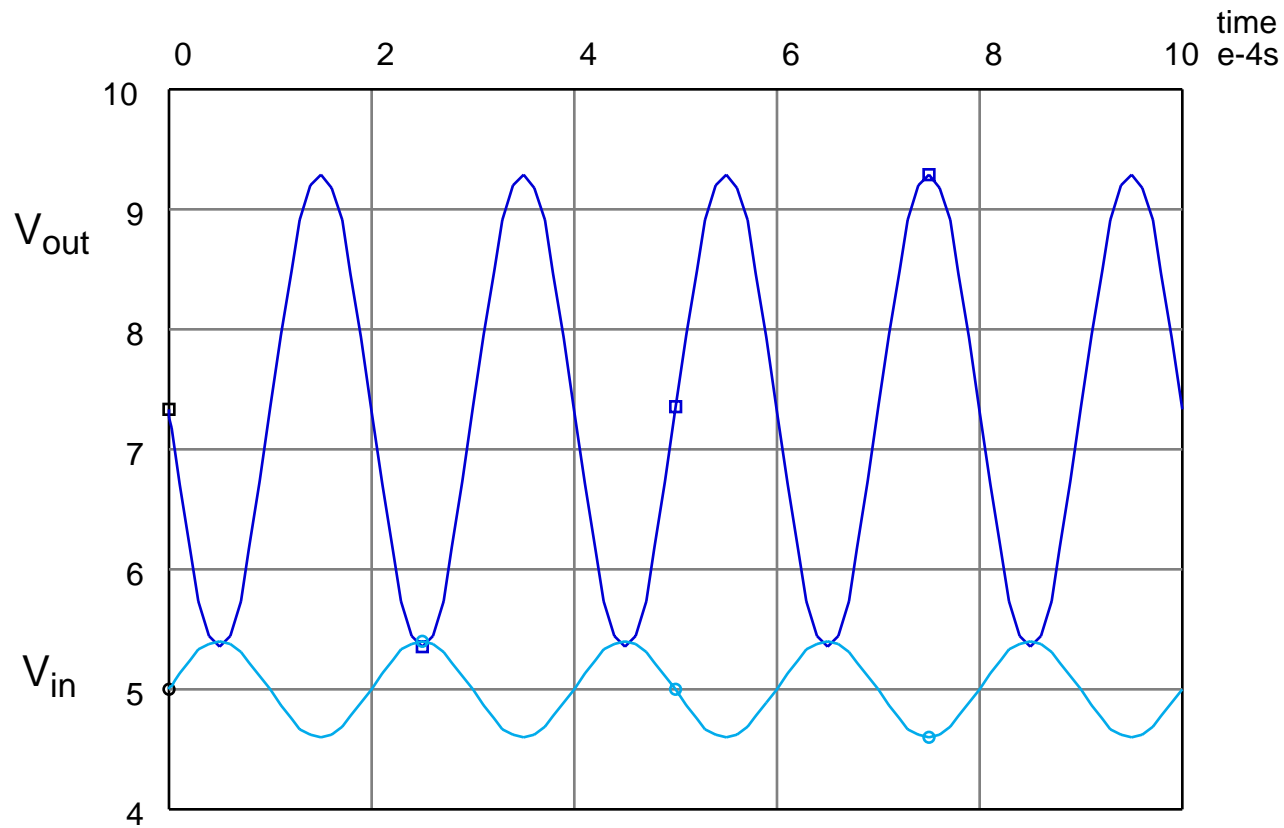
dc Solution of FET Amplifier

- Response for a 5kHz, 0.2v peak ac input signal



dc Solution of FET Amplifier

- The output signal is somewhat distorted for a 0.4v peak ac input



Small Signal Assumption

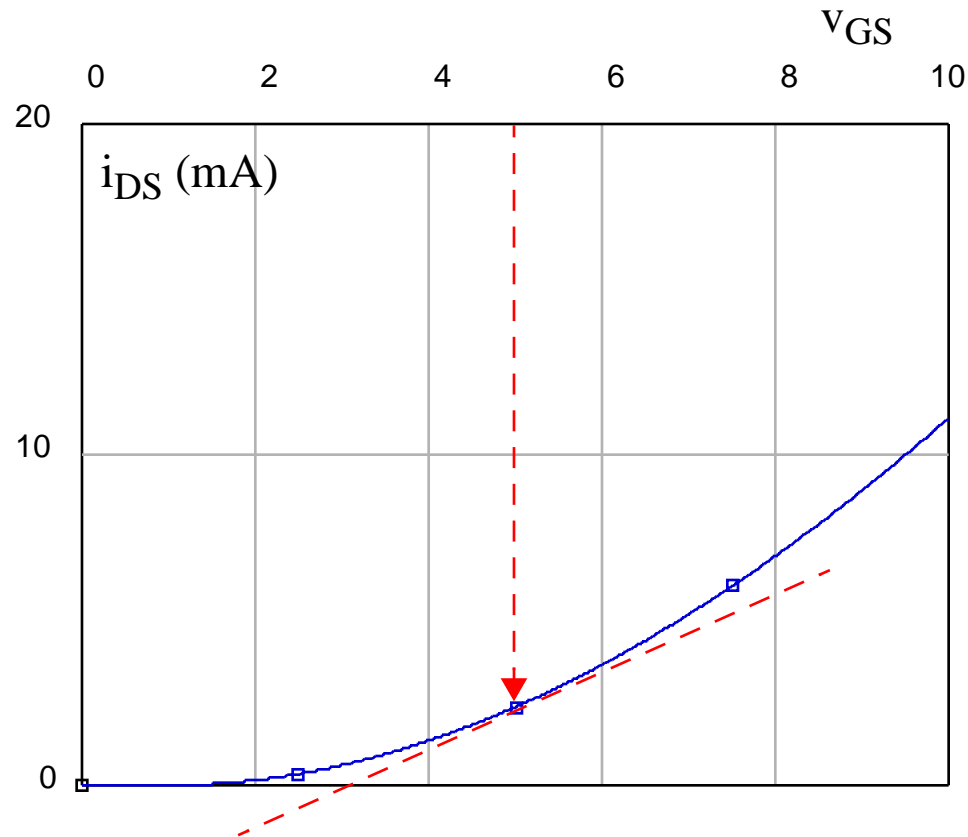
- The distortion is due to the nonlinear effects when the ac v_{gs} is too large:

bias point equations: $I_D = K(V_{GS} - V_t)^2$ $V_D = V_{DD} - R_D I_D$

ac & dc equations: $v_{GS} = V_{GS} + v_{gs}$ $i_D = K(v_{GS} - V_t)^2$

Transconductance -- Gain

- The transconductance, g_m , for a MOSFET is much smaller than that for a BJT which uses the same silicon area (BJT approx. 100 times better)



$$g_m = \left. \frac{\partial i_D}{\partial v_{GS}} \right|_{v_{GS} = V_{GS}}$$

Transconductance -- Gain

- BJT g_m 's are independent of area dimensions
- FET g_m 's are dependent on channel W and L dimensions

$$g_m = \left. \frac{\partial i_D}{\partial v_{GS}} \right|_{v_{GS} = V_{GS}} = 2K(V_{GS} - V_t) = \mu_n C_{ox} \frac{W}{L} (V_{GS} - V_t)$$

Small Signal Voltage Gain

$$v_D = V_{DD} - R_D i_D = V_{DD} - R_D (I_D + i_d)$$

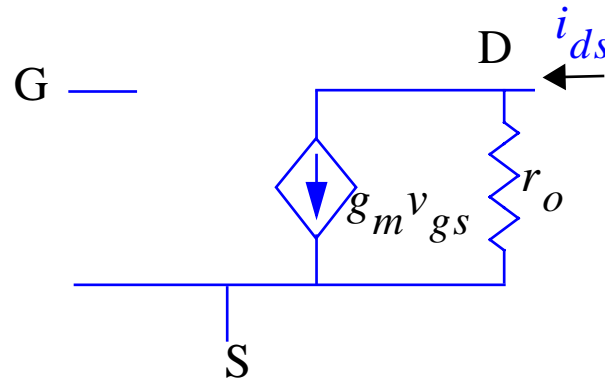
- Under the small signal assumption:

$$v_d = -R_D i_d = -g_m R_D v_{gs}$$

$$\frac{v_d}{v_{gs}} = -g_m R_D$$

Small Signal Model

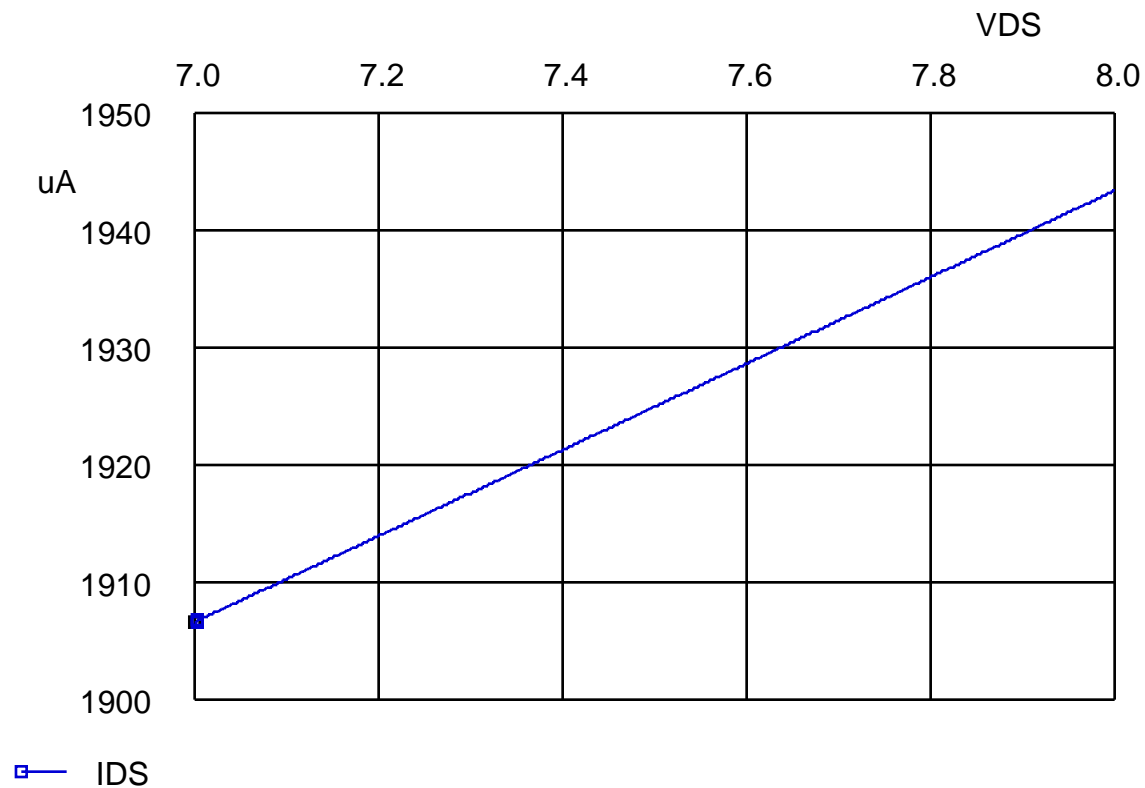
- The small signal model is very similar to that for the BJT amplifier:



- r_o is the drain-source voltage change with change in i_{ds} due to channel length modulation.

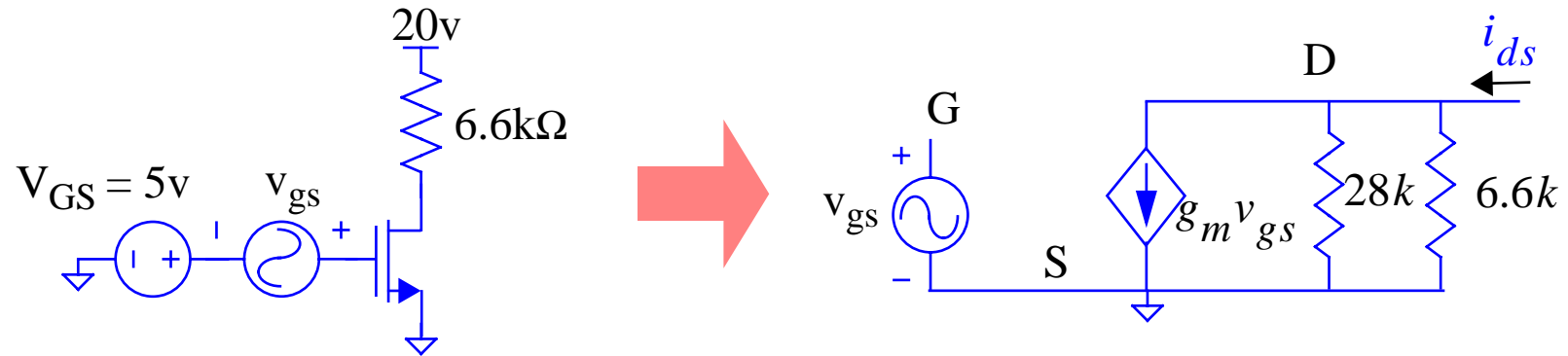
Channel Length Modulation

- Given λ and the bias point, we can calculate r_o
- For our example, we can estimate r_o from an enlarged view of I_{DS} vs. V_{DS} at the bias point (with $V_{GS}=5\text{v}$)



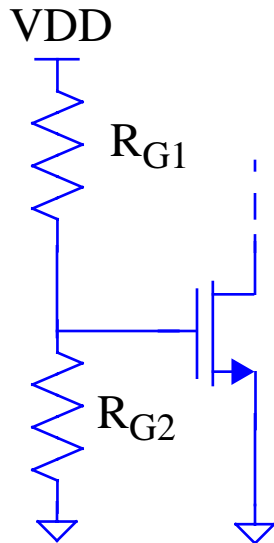
Small Signal Model

- Short the dc supplies and analyze the small signal equivalent ckt:

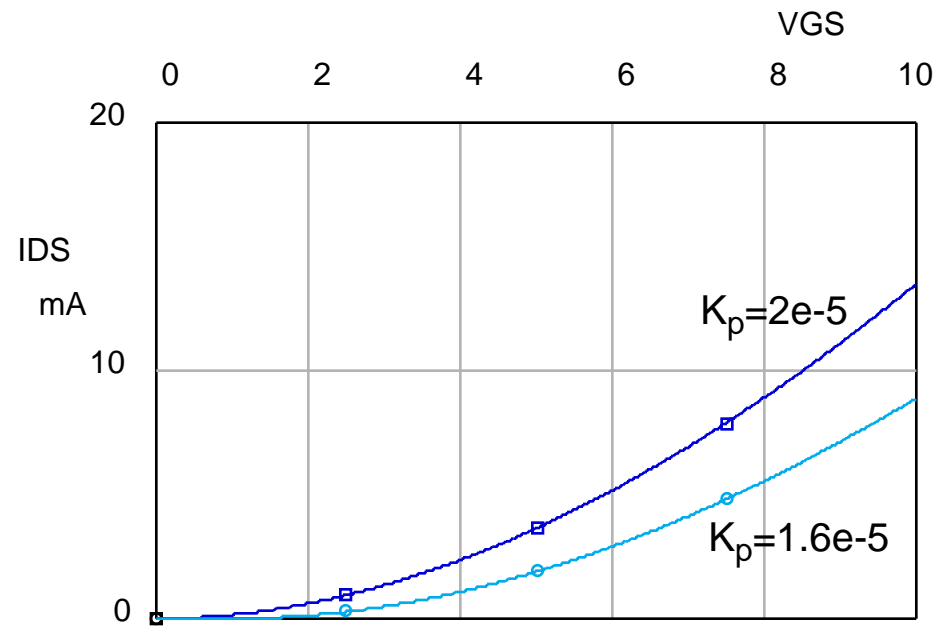


Biasing

- Since I_D determines g_m we'd like to bias the transistor so that the small signal gain remains as stable as possible with variations in temperature and process

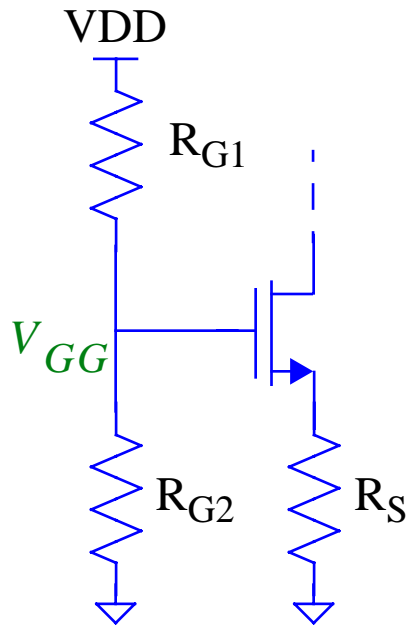


$$V_{GG} = V_{DD} \frac{R_{G2}}{R_{G1} + R_{G2}}$$



Negative Feedback Resistor

- R_S provides negative feedback for unwanted changes in I_{DS} due to process variations or temperature fluctuations

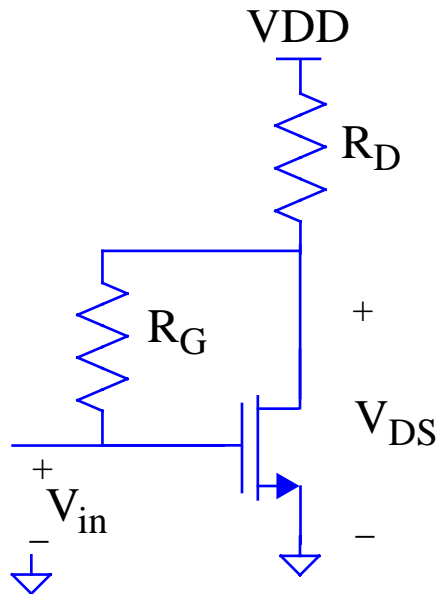


Negative Feedback Resistor

- We can get a similar negative feedback effect with a drain to gate bias resistor
- This resistor guarantees that the transistor is biased in the saturation region --
- why?

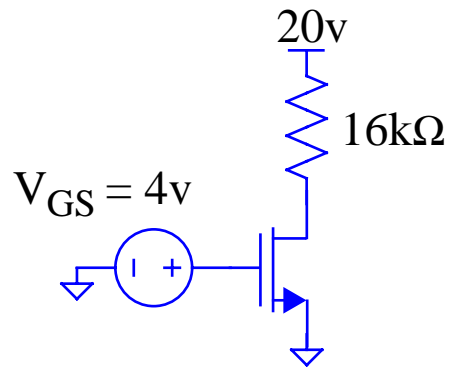
Find the R_D which establishes a $1\text{mA } I_D$

$$K=0.25\text{mA/V}^2 \quad V_{DD}=20\text{V} \quad V_t = 2\text{V}$$



No negative Feedback Resistor

- What is the change in I_D for the circuit below if the threshold voltage changes from 2V to 3V?



Negative Feedback Resistor

- But this change is much less with negative feedback control

